

**Notice of References Cited**

Application/Control No.

10/538,470

Applicant(s)/Patent Under  
Reexamination  
IWAMURA, EIJI

Examiner

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Art Unit

1793

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,844,785	07-1989	Kitabatake et al.	204/192.11
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zhang, et al., Residual stress characterization of diamond-like carbon coatings by an X-ray diffraction method, Surface Coatings Technology 1999; 122: 219-224
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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